

Hierarchical defect level test quality analysis

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmicz, W.; Lobur, M.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** VILAB User Forum 2000 / [11] p

Hierarchical test generation for digital circuits represented by Decision Diagrams : thesis on informatics and system engineering

Raik, Jaan 2001 https://www.ester.ee/record=b1578107*est

Lihsad veebisaitide testimisvahendid

Tepandi, Jaak; Tepandi, Liisi A & A 2000 / 4, lk. 14-21 https://artiklid.elnet.ee/record=b1004807*est

Piecewise linearly approximated sine wave for dynamic quality tests of A/D converters

Land, Raul Proceedings of the Estonian Academy of Sciences. Engineering 2000 / 2, p. 113-119 : ill
https://artiklid.elnet.ee/record=b1004041*est

Tarkvara kvaliteet ja standardid

Tepandi, Jaak 1999 https://www.ester.ee/record=b1331246*est